

Notice of References Cited

Application/Control No.

10/694,465

Applicant(s)/Patent Under
Reexamination
GALLATIN ET AL.

Examiner

Shambhavi Patel

Art Unit

2128

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,223,139	04-2001	Wong et al.	703/5
*	C	US-6,374,396	04-2002	Baggenstoss et al.	716/19
*	D	US-5,182,718	01-1993	Harafuji et al.	430/30
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Fukuda et al. "Determination of High-Order Lens Aberration Using Phase/Amplitude Linear Algebra", 1999.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.